



Advanced Technologies for Microwave and Wireless Sensors

Guest Editor:

Dr. Benjamin Potelon

Univ Brest, CNRS, Lab-STICC,
29238 Brest, France

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Message from the Guest Editor

The rapid emergence of the IoT (Internet of Things), associated with the increased capacity of systems to process large volumes of data (AI, Machine Learning, Big data, etc.), has paved the way and reinforced the need for a new generation of sensors. Indeed, the constant search for streaming and live information has called for a new paradigm where dealing with high volumes of data is no longer a problem as long as that data is generally reliable. In this context, microwave sensors can provide interesting characteristics such as non-invasiveness, continuous measurement, and of course the ability to follow structural, chemical, mechanical, or physical properties specifically related to RF-waves. This Special Issue focuses on recent advances in the design of microwave sensors under the topological, technological, or practical aspects, as well as on the advantages for various applications, including, for instance, biomedical or industrial fields.

- Microwave and RF sensors
- Wireless technologies
- Microwave monitoring
- Microwave passive sensing devices
- Microwave active sensing devices
- Microwave Sensing applications
- RF imaging
- Radar sensing
- Bio-sensors
- Bio-electromagnetism





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Prof. Dr. Giulio Nicola Cerullo

Dipartimento di Fisica,
Politecnico di Milano, Piazza L.
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Message from the Editor-in-Chief

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